



Schedule 1  
to  
Grant of Security Interest (Patents)  
Dated as of March 18, 1998

**Robotic Vision Systems, Inc.**

<u>Patent No.</u>	<u>Title</u>
4259017	Methods for use in Definition of Object Surfaces
4259589	Generation of Contiguous Data Files of 3-D Information
4269513	Arrangement for Sensing the Surface of an Object Independent of the Reflectance Characteristics of the Surface
4285754	Method and Apparatus of Producing Planar Elements in the Construction of Surfaces and Bodies
4286852	Recording Images of a 3-D Surface by Focusing
4292724	Arrangement for Constructing Surfaces and Bodies
4335962	Apparatus and Method for Determining Spatial Information
4337566	Gauging System for Machining
4355447	Gauging System for Sculptured Surfaces
4357108	Method for Reproduction of Object Surface
4392182	Arrangement for Scanning Points in Space
4396945	Method for Sensing Position and Orientation of Elements in Space
4402608	Room Scanning System Using Multiple Cameras and Projector Sensors
4443705	Method for Locating Points in a 3-D Surface Using Light Intensity Variations
4443706	Method for Locating Points in a 3-D Surface Using Light Intensity Variations
4488173	Method of Sensing the Position and Orientation of Elements in Space
5723869	Multichannel Position Sensing Detector

Robotic Vision Systems, Inc.

<u>Patent No.</u>	<u>Title</u>
4508452	Arrangements for Sensing the Characteristics of a Surface and Determining Position of Points Thereon
4511252	Arrangements for Sensing the Geometric Characteristics of an Object
4529316	Arrangement for Eliminating Erroneous Data in 3-D Optical Sensors
4533828	Arrangement for Increasing the Dynamic Range of Optical Inspection Devices to Accomodate Varying Surface Reflectivity Characteristics
4573758	Beam Deflection System
4590367	Arrangement for the Expansion of the Dynamic Range of Optical Devices
4591253	Adaptive Vision System
4594001	Detection of 3-D Information with a Projected Plane of Light
4629324	Arrangement for Measuring Depth Based on Lens Focusing
4630910	Method of Measuring in 3-D at High Speed
4634279	Method of 3-D Measurement with Few Projection Patterns
4634278	Method of 3-D Measurement with Few Projected Patterns
4637058	Location of Objects Without Use of Salient Features
4640620	Arrangement for Rapid Depth Measurement Using Lens Focusing
4643578	Arrangement for Scanned 3-D Measurement
4648717	Method of 3-D Measurement with Few Projection Patterns
4652205	Robot Cell Safety System
4652749	Optical Coordinate Measurement Systems with Dual Path Reflecting Means
4657393	Pattern Optimization When Measuring Depth to Surface Using Lens Focusing
4682894	Calibration of 3-D Space
4689480	Arrangement of Improved Scanned 3-D Measurement
4225228	Surface Coating for Optical Inspection

### GRANT OF SECURITY INTEREST (PATENTS)

The undersigned, a Delaware corporation (the "*Grantor*"), is obligated to THE BANK OF NEW YORK, as Administrative Agent (the "*Secured Party*"), and has entered into a Security Agreement, dated as of March 18, 1998 (as amended, supplemented or otherwise modified from time to time, the "*Security Agreement*"), in favor of the Secured Party.

Pursuant to the Security Agreement, the Grantor granted to the Administrative Agent a security interest in all of the right, title and interest of the Grantor in and to (i) all letters patent and all applications therefor listed on Schedule 1 and all reissues, continuations, divisions, continuations-in-part, renewals or extensions thereof (the "*Patents*") together with all and the inventions disclosed or claimed therein, including the right to make, use and/or sell the inventions disclosed or claimed therein and (iii) all proceeds thereof, any and all causes of action which may exist by reason of infringement thereof (the "*Collateral*"), to secure the prompt payment, performance and observance of its Obligations (as defined in the Security Agreement).

For good and valuable consideration, the receipt of which is hereby acknowledged, and for the purpose of recording the grant of the security interest as aforesaid, the Grantor does hereby further assign to the Secured Party, and grant to the Secured Party a security interest in, the Patents to secure the prompt payment, performance and observance of its Obligations (as defined in the Security Agreement).

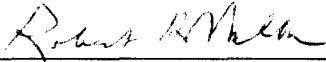
The Grantor does hereby further acknowledge and affirm that the rights and remedies of the Secured Party with respect to the assignment of and security interest in the Collateral made and granted hereby are set forth in the Security Agreement, the terms and provisions of which are hereby incorporated herein by reference as if fully set forth herein.

Upon the cash payment in full of all its Obligations (as defined in the Security Agreement), the Secured Party will take whatever actions are necessary at the Grantor's expense to release or reconvey to Grantor all right, title and interest of the Grantor in and to the Collateral.

The Administrative Agent's address is: One Wall Street, New York, New York 10286.

IN WITNESS WHEREOF, the Grantor has caused this Grant of Security Interest to be duly executed by its duly authorized officer as of the 18th day of March, 1998.

ROBOTIC VISION SYSTEMS, INC.

By:   
Name: Robert H. Walker  
Title: Executive Vice President

STATE OF NEW YORK     )  
                                  ) ss.:  
COUNTY OF NEW YORK )

On this 18th day of March, 1998, before me personally came Robert H. Walker, to me known, who, being by me duly sworn, did depose and say that he resides at 5 Saneck Road, St. James, NY 11780; that he is the Executive Vice President of ROBOTIC VISION SYSTEMS, INC., the corporation described in and which executed the above instrument, and that he signed his name thereto by order of the board of directors of thereof.

Lilian M. Tompkins  
Notary Public

LILIAN M. TOMPKINS  
Notary Public, State of New York  
No. 01TO4709336  
Qualified in New York County 98  
Commission Expires April 30, 1998

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4225228	Surface Coating for Optical Inspection



Robotic Vision Systems, Inc.

<u>Patent No.</u>	<u>Title</u>
4783166	Arrangement for Improving Visual Detection of Painted Areas Relative to Surrounding Material
4822163	Tracking Vision Sensor
4830443	3-d Volumetric Sensor
4845639	Robotic Sealant Calibration
4854698	3-D Measurement Via Multiple Gating
4895434	Apparatus and Method for 3-D Measurement Using Holographic Scanning
4901576	Acoustic Leak Detection System
4925308	Calibration of 3-D Space
4954059	Sealant Bead Profile Control
4967370	Robot and Sensor Error Determination System
4991968	3-D Object Surface Determination with Automatic Sensor Control
4999785	Method and Apparatus for Evaluating Defects of an Object
5028799	Method and Apparatus for Evaluating Defects of an Object
5018803	3-D Volumetric Sensor
4991772	Multiple Air Stream Control
5118192	System for 3-D Inspection of Objects
5175018	Automated Masking Device for Robotic Painting/Coating
5216259	Apparatus and Method for Improved Determination of the Spatial Locations of Object Surface Points
5263567	Horizontal Vibrator Method for Use in Orienting Articles
5349378	Context Independent Fusion of Range and Intensity Imagery
5371375	Method of Obtaining 3-D Measurement of Multi Parts or Devices in a Multi Pocketed Tray
5463227	Method for Obtaining 3-Dimensional Data from Multiple Parts or Devices in a Multi-Pocketed Tray
5465152	Method for Coplanarity Inspection of Package or Substrate Warpage for Ball Grid Arrays, Column Arrays and Similar Structures

Robotic Vision Systems, Inc.

<u>Patent No.</u>	<u>Title</u>
5475370	System for Detecting Ice of Snow on Surface which Specularly Reflects Light
5528287	Multi-Level Retarder Plate Polarization Dependent Imaging
5532738	System for Detecting Ice of Snow on Surface Which Specularly Reflects Light
5554858	Segmented Position Sensing Detector for Reducing Non-Uniformly Distributed Stray Light from a Spot Image
5576948	Machine Vision for Adaptive Laser Beam Steering
5589822	System for Detecting Ice or Snow on Surface Which Specularly Reflects Light
5600150	Method for Obtaining 3-D Data from Semiconductor Devices in a Row/Column Array and Control of Manufacturing
5617076	System for Detecting Ice or Snow on Surface Which Specularly Reflects Light
5648853	System for Inspecting Pin Grid Arrays
5668630	Dual Bed Scanner with Reduced Transport Time
5691810	Dual Bed Scanner with Reduced Transport Time
5691544	Apparatus for Obtaining Three-Dimensional Data from Multiple Parts or Devices in a Multi-Pocketed Tray

Schedule 1  
to  
Grant of Security Interest (Trademarks)  
Dated as of March 18, 1998

CiMatrix LLC

<u>Mark</u>	<u>Registration No.</u>	<u>Registration Date</u>
CiPRO	1953696	January 30, 1996
CiMAX	1977185	May 28, 1996
CIX	1977186	May 28, 1996
OmniCix	1984536	June 2, 1996
Mag Barcode	1360356	September 17, 1985
CIVIEW	75-103,500 (Serial No.)	May 13, 1996 (Filed)